
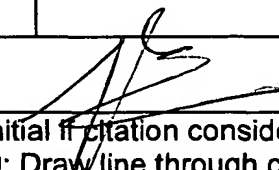



<b>FORM PTO-1449 (SUBSTITUTE)</b>  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE          STATEMENT BY APPLICANT</b> (37 CFR 1.98(b))				Attorney Docket No.: P2001,0082 Appl. No.:  Applicant: JÜRGEN MÜLLER  Filing Date: August 8, 2003 Group Art Unit: 2828			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
PR	A	5,822,356	10/13/98	Jewell	<del>          </del>	<del>          </del>	<del>          </del>
	B	5,881,085	3/9/99	Jewell	<del>          </del>	<del>          </del>	<del>          </del>
	C	6,144,682	11/7/00	Sun	<del>          </del>	<del>          </del>	<del>          </del>
	D	5,493,577	2/20/96	Choquette et al.	<del>          </del>	<del>          </del>	<del>          </del>
	E						
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	I						
<b>FOREIGN PATENT DOCUMENT</b>							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
	J						
	K						
	L						
	M						
	N						
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
PR		Wu, Y. A. et al.: "High-Yield Processing and Single-Mode Operation of Passive Antiguide Region Vertical-Cavity Lasers", IEEE Journal of Selected Topics in Quantum Electronics, Vol. 3, No. 2, April 1997, pp. 429-434					
PR		Michalzik, R. et al.: "High-Bit-Rate Data Transmission with Short-Wavelength Oxidized VCSEL's: Toward Bias-Free Operation", IEEE Journal of Selected Topics in Quantum Electronics, Vol. 3, No. 2, April 1997, pp. 396-404					
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>			
				4/29/03			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
pn		Zhou, D. et al.: "Simplified-Antiresonant Reflecting Optical Waveguide-Type Vertical-Cavity Surface-Emitting Lasers", American Institute of Physics, Applied Physics Letters, Vol. 76, No. 13, March 27, 2000, pp. 1659-1661					
pn		Morgan, R. A. et al.: "Hybrid Dielectric/AlGaAs Mirror Spatially Filtered Vertical Cavity Top-Surface Emitting Laser", American Institute of Physics, Applied Physics Letters, Vol. 66, No. 10, March 6, 1995, pp. 1157-1159					
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>			
				4/29/05			
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	J						
	K						
	L						
	M						
	N						
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
		Nishiyama, N. et al.: "Multi-Oxide Layer Structure for Single-Mode Operation in Vertical-Cavity Surface-Emitting Lasers", IEEE Photonics Technology Letters, Vol. 12, No. 6, June 2000, pp. 606-609					
EXAMINER				DATE CONSIDERED			
							
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